

N-channel TrenchMOS standard level FET Rev. 4 — 4 January 2012

Product data sheet

Product profile 1.

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant

Suitable for standard level gate drive sources

Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- 12 V, 24 V and 42 V loads
- Automotive systems

General purpose power switching

Motors, lamps and solenoids

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	100	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see Figure 1; see Figure 3	<u>[1]</u>	-	-	75	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	300	W
Static charact	teristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C};$ see Figure 11; see Figure 12		-	8.6	10	mΩ



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Table 1.	Quick reference data c	continued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 80 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 13</u>	-	22	-	nC
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$\begin{array}{l} I_D = 75 \text{ A}; \ V_{sup} \leq 100 \text{ V}; \\ R_{GS} = 50 \ \Omega; \ V_{GS} = 10 \text{ V}; \\ T_{j(init)} = 25 \ ^\circ\text{C}; \\ unclamped \end{array}$	-	-	629	mJ

. . .

[1] Continuous current is limited by package.

Pinning information 2.

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	D D
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT78A (TO-220AB)	

Ordering information 3.

Table 3. Ordering	g information		
Type number	Package		
	Name	Description	Version
BUK7510-100B	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A

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4. Limiting values

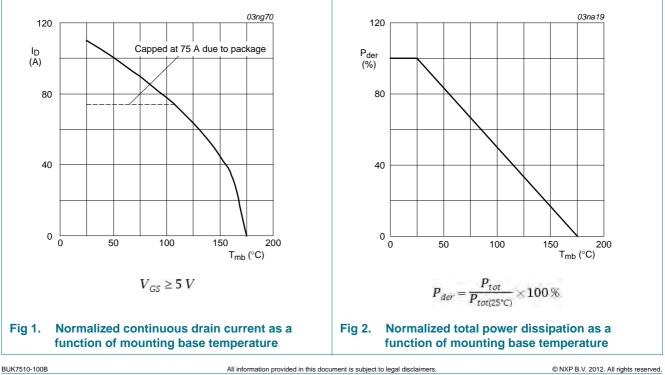
Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	100	V
V _{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	100	V
V _{GS}	gate-source voltage		-20	20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ;	<u>[1]</u> _	110	А
		see Figure 3	[2] _	75	А
		T_{mb} = 100 °C; V_{GS} = 10 V; see Figure 1	[2] _	75	А
I _{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \ \mu$ s; see <u>Figure 3</u>	-	438	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	300	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	n diode				
I _S	source current	T _{mb} = 25 °C	<u>[1]</u> _	110	А
			[2] _	75	А
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	438	А
Avalanche r	uggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 75 A; $V_{sup} \le 100$ V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-	629	mJ

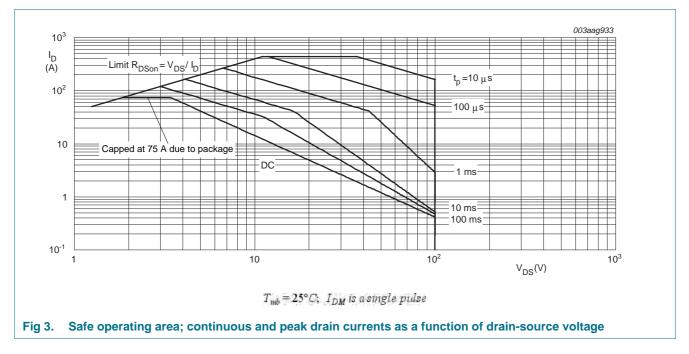
[1] Current is limited by power dissipation chip rating.

[2] Continuous current is limited by package.



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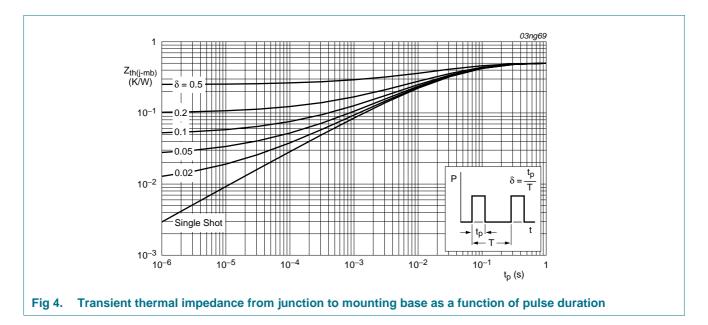
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5. Thermal characteristics

Table 5.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	0.5	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W



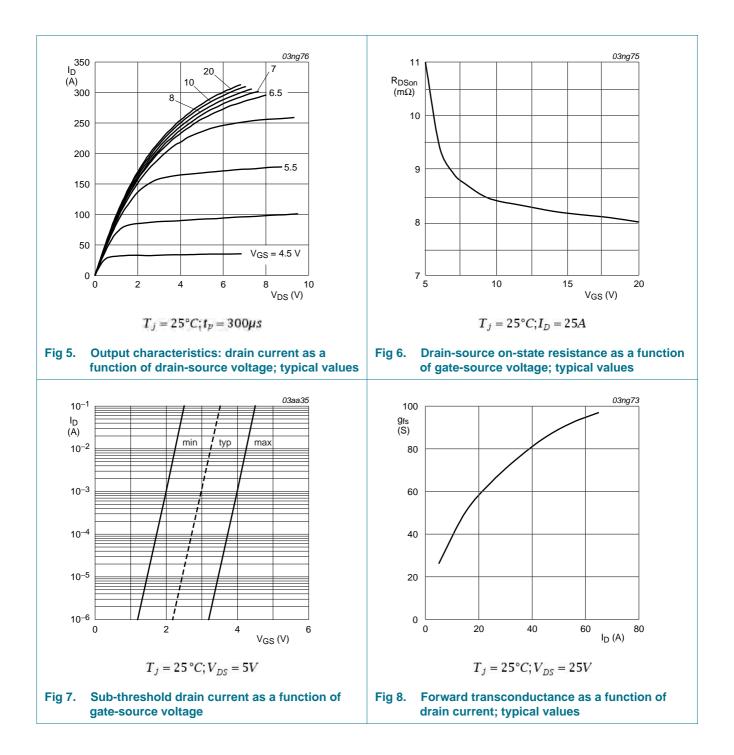
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6. Characteristics

	Table 6.	Characteristics	A 1111		-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$\begin{tabular}{ c $	Static cha						
$ \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	V _{(BR)DSS}			100	-	-	V
$ \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$		breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	89	-	-	V
$ \frac{\sec \ Figure \ 10}{ _{0} = 1 \ mA; \ V_{DS} = V_{GS}; \ T_{j} = 55 \ ^{\circ}C; \ - \ - \ - \ - \ - \ - \ - \ - \ - \ $	V _{GS(th)}	-	,	1	-	-	V
				2	3	4	V
$ \begin{array}{ c c c c c c } \hline V_{DS} = 100 \ V; \ V_{GS} = 0 \ V; \ T_j = 175 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = 20 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = -20 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = -20 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = 10 \ V; \ V_{DS} = 25 \ A; \ T_j = 175 \ ^{\circ}C; & - & 25 & m\Omega \\ \hline see \ Figure 11; \ see \ Figure 12 & - & - & 25 & m\Omega \\ \hline see \ Figure 11; \ see \ Figure 12 & - & - & 25 & m\Omega \\ \hline V_{GS} = 10 \ V; \ V_{DS} = 25 \ A; \ T_j = 25 \ ^{\circ}C; & - & 8.6 & 10 & m\Omega \\ \hline Dynamic \ characteristics & & & & & & & & & \\ \hline Dynamic \ characteristics & & & & & & & & & & & \\ \hline Dynamic \ characteristics & & & & & & & & & & & & & \\ \hline Dynamic \ characteristics & & & & & & & & & & & & & & & & & & &$,	-	-	4.4	V
	I _{DSS}	drain leakage current	V _{DS} = 100 V; V _{GS} = 0 V; T _j = 25 °C	-	0.02	1	μA
$ \begin{array}{ c c c c c c } \hline V_{GS} = -20 \ V; \ V_{DS} = 0 \ V; \ T_{j} = 25 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline R_{DSon} & drain-source on-state resistance & V_{GS} = 10 \ V; \ I_{D} = 25 \ A; \ T_{j} = 175 \ ^{\circ}C; & - & - & 25 & m\Omega \\ \hline see \ Figure 11; \ see \ Figure 12 & V_{GS} = 10 \ V; \ T_{D} = 25 \ A; \ T_{j} = 25 \ ^{\circ}C; \\ see \ Figure 11; \ see \ Figure 12 & - & - & 8.6 & 10 & m\Omega \\ \hline Dynamic \ characteristics & & & & & & & & & & & & & & & & & & &$			V _{DS} = 100 V; V _{GS} = 0 V; T _j = 175 °C	-	-	500	μA
	I _{GSS}	gate leakage current	V _{GS} = 20 V; V _{DS} = 0 V; T _j = 25 °C	-	2	100	nA
$ \begin{array}{ c c c c c c } resistance & see Figure 11; see Figure 12 \\ \hline V_{GS} = 10 \ V; \ I_{D} = 25 \ A; \ T_{J} = 25 \ ^{\circ}C; \\ see Figure 11; see Figure 12 \\ \hline V_{GS} = 10 \ V; \ I_{D} = 25 \ A; \ V_{DS} = 80 \ V; \ V_{GS} = 10 \ V; \\ \hline Q_{GS} & gate-source charge \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 13 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 13 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 13 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 13 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C; see Figure 14 \\ \hline T_{J} = 25 \ ^{\circ}C \\ \hline T_{J} =$			V _{GS} = -20 V; V _{DS} = 0 V; T _j = 25 °C	-	2	100	nA
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$				-	-	25	mΩ
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$				-	8.6	10	mΩ
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Dynamic	characteristics					
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Q _{G(tot)}	total gate charge	I _D = 25 A; V _{DS} = 80 V; V _{GS} = 10 V;	-	80	-	nC
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 13</u>	-	18	-	nC
$ \begin{array}{cccc} C_{oss} & output capacitance \\ C_{rss} & reverse transfer \\ capacitance \\ t_{d(on)} & turn-on delay time \\ t_r & rise time \\ t_{d(off)} & turn-off delay time \\ t_f & fall time \\ L_D & internal drain \\ inductance & \\ \end{array} \begin{array}{cccc} From contact screw on mounting base to \\ centre of die SOT78; T_j = 25 °C \\ \hline from drain lead 6 mm from package \\ to centre of die; T_j = 25 °C \\ \hline from source lead to source bond pad; \\ T_j = 25 °C \\ \hline from source lead to source bond pad; \\ T_j = 25 °C \\ \hline Source-drain diode \\ \hline V_{SD} & source-drain voltage \\ t_{rr} & reverse recovery time \\ \hline I_S = 20 A; dIs/dt = -100 A/\mus; V_{GS} = -10 V; \\ \hline I_S =$	Q _{GD}	gate-drain charge		-	22	-	nC
$ \begin{array}{cccc} C_{oss} & output capacitance \\ C_{rss} & reverse transfer \\ capacitance \\ t_{d(on)} & turn-on delay time \\ t_r & rise time \\ t_{d(off)} & turn-off delay time \\ t_f & fall time \\ L_D & internal drain \\ inductance & \\ \end{array} \begin{array}{cccc} From contact screw on mounting base to \\ centre of die SOT78; T_j = 25 °C \\ \hline from drain lead 6 mm from package \\ to centre of die; T_j = 25 °C \\ \hline from source lead to source bond pad; \\ T_j = 25 °C \\ \hline from source lead to source bond pad; \\ T_j = 25 °C \\ \hline Source-drain diode \\ \hline V_{SD} & source-drain voltage \\ t_{rr} & reverse recovery time \\ \hline I_S = 20 A; dIs/dt = -100 A/\mus; V_{GS} = -10 V; \\ \hline I_S =$	C _{iss}	input capacitance		-	5080	6773	pF
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 14}{14}$	-	677	812	pF
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	C _{rss}			-	168	230	pF
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	33	-	ns
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$		rise time	$R_{G(ext)} = 10 \ \Omega; T_j = 25 \ ^{\circ}C$	-	45	-	ns
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	t _{d(off)}	turn-off delay time		-	120	-	ns
$ \begin{array}{c} \mbox{inductance} & \mbox{centre of die SOT78; } T_j = 25 \ ^\circ C \\ \hline from drain lead 6 mm from package & - & 4.5 & - & nH \\ \mbox{to centre of die; } T_j = 25 \ ^\circ C \\ \hline L_S & \mbox{internal source} & from source lead to source bond pad; & - & 7.5 & - & nH \\ \hline T_j = 25 \ ^\circ C \\ \hline Source-drain diode \\ \hline V_{SD} & \mbox{source-drain voltage} & I_S = 40 \ A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ C; & - & 0.85 & 1.2 \ V \\ \hline see \ Figure 15 \\ \hline t_{rr} & reverse recovery time & I_S = 20 \ A; \ dI_S/dt = -100 \ A/\mu s; \ V_{GS} = -10 \ V; & - & 69 \ - & ns \\ \hline \end{array} $		fall time		-	36	-	ns
to centre of die; $T_j = 25 \text{ °C}$ Lsinternal source inductancefrom source lead to source bond pad; $T_j = 25 \text{ °C}$ 7.5-nHSource-drain diodeVSource-drain voltageIs = 40 A; V_{GS} = 0 V; T_j = 25 °C; see Figure 15-0.851.2Vtrrreverse recovery timeIs = 20 A; dIs/dt = -100 A/µs; V_{GS} = -10 V; $20 \text{ V} \text{ fr} = 25 \text{ °C}$ -69-ns	L _D			-	3.5	-	nH
Lsinternal source inductancefrom source lead to source bond pad; $T_j = 25 \ ^{\circ}C$ -7.5-nHSource-drain diodeV_{SD}source-drain voltageI_S = 40 A; V_{GS} = 0 V; T_j = 25 \ ^{\circ}C; see Figure 15-0.851.2Vtrrreverse recovery timeI_S = 20 A; dI_S/dt = -100 A/µs; V_{GS} = -10 V; $20 V/t T = 25 \ ^{\circ}C$ -69-ns			from drain lead 6 mm from package	-	4.5	-	nH
Source-drain diode V_{SD} source-drain voltage $I_S = 40 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see Figure 15-0.851.2V t_{rr} reverse recovery time $I_S = 20 \text{ A}; \text{ dI}_S/\text{dt} = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = -10 \text{ V};$ -69-ns	L _S		from source lead to source bond pad;	-	7.5	-	nH
see Figure 15 t_{rr} reverse recovery time $I_S = 20 \text{ A}; \text{ dI}_S/\text{dt} = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = -10 \text{ V}; - 69 - \text{ns}$	Source-d	rain diode					
t_{rr} reverse recovery time $I_S = 20 \text{ A}; \text{ dI}_S/\text{dt} = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = -10 \text{ V};$ - 69 - ns	V _{SD}	source-drain voltage		-	0.85	1.2	V
V 20.V/ T 25.%C	t _{rr}	reverse recovery time		-	69	-	ns
		recovered charge		-	212	-	nC

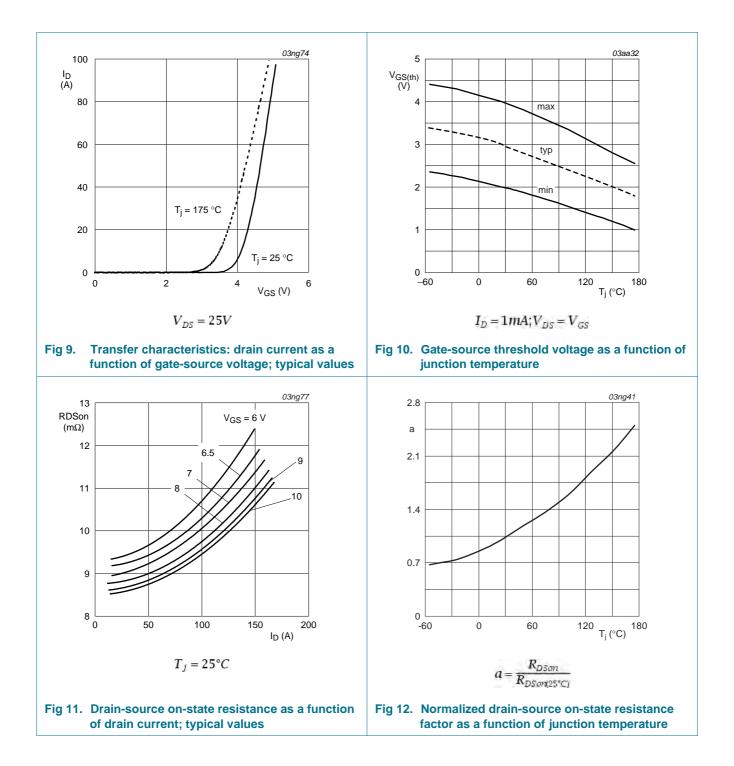
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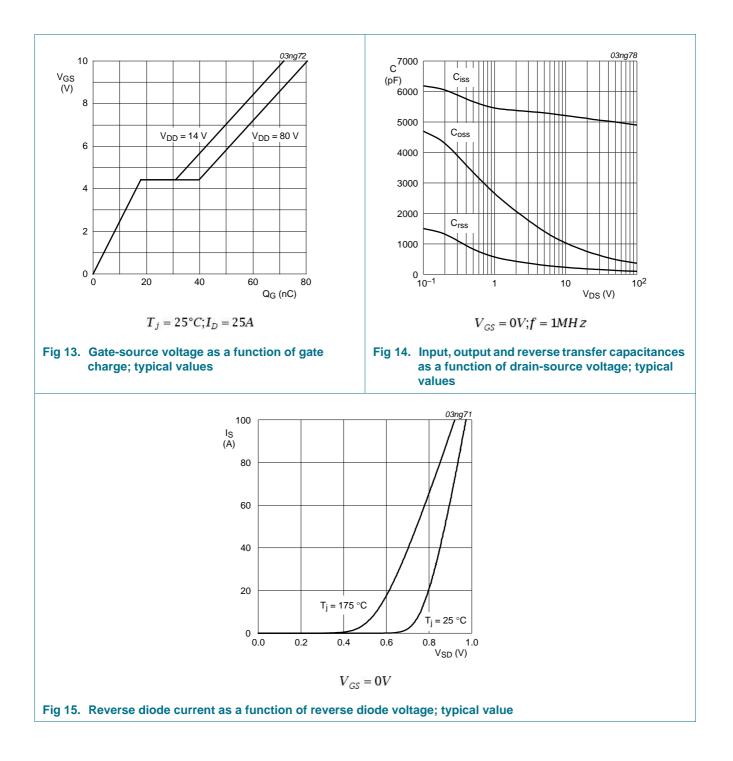
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7. Package outline

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							0 Lu	sca		0 mm 						
			ho origi	nal dime		D	D ₁	Е	е	L	L1 ⁽¹⁾	L ₂	n	q	Q]
		nm are t		b₄	C C		21	-		15.0	-1 .7 3.30	max. 3.0	р 3.8	ч 3.0	2.6	-
UNIT	Α	A ₁	b	b 1 1.3	c 0.7	15.8	6.4	10.3	0 - 1			3.0	3.6			
				b1 1.3 1.0	c 0.7 0.4	15.8 15.2	6.4 5.9	10.3 9.7	2.54	13.5	2.79		3.0	2.7	2.2	
UNIT mm	A 4.5	A ₁ 1.39	b 0.9	1.3	0.7				2.54	13.5	2.79		3.0	2.7	2.2	
UNIT mm lote . Termi	A 4.5 4.1 nals in th	A ₁ 1.39	b 0.9 0.6	1.3 1.0	0.7	15.2	5.9	9.7	2.54	13.5	2.79			I		
UNIT mm Note I. Termi	A 4.5 4.1	A ₁ 1.39 1.27	b 0.9 0.6	1.3 1.0	0.7 0.4	15.2		9.7 NCES	2.54	13.5	2.79		EUR	OPEAN ECTION		ISSUE DATE

Fig 16. Package outline SOT78A (TO-220AB)

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8. Revision history

Table 7.Revision	history				
Document ID	Release date	Data sheet status	Change notice	Supersedes	
BUK7510-100B v.4	20120104	Product data sheet	-	BUK7510-100B_3	
Modifications: • Various changes to content.					
BUK7510-100B_3	20100414	Product data sheet	-	BUK75/7610_100B_2	

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9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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N-channel TrenchMOS standard level FET

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